Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/664,112	LYNCH, JONATHAN
Examiner	Art Unit
Henry K. Choe	2817

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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